

### Features

- Easy to use, compatible with standard gate drivers
- Superior reliability with  $BV_{DSS}$  over 1500V
- Low  $Q_{RR}$ , no free-wheeling diode required
- Excellent  $Q_G \times R_{DS(on)}$  figure of merit (FOM)
- Low switching loss
- RoHS compliant and Halogen-free

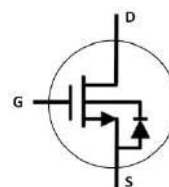
### Application

- High efficiency power supplies
- Telecom and datacom
- Servo motors
- Automotive

### Product Summary



$V_{DS}$	900	V
$R_{DS(on),Max} @ V_{GS} = 8V$	175	mΩ
$I_D$	23	A



### Maximum ratings, at $T_C=25^\circ\text{C}$ , unless otherwise specified

Symbol	Parameter		Limit Value	Unit
$I_D$	Continuous drain current @ $T_C=25^\circ\text{C}$		23	A
	Continuous drain current @ $T_C=100^\circ\text{C}$		15	A
$I_{DM}$	Pulsed drain current @ $T_C=25^\circ\text{C}$ (pulse width: 10us)		92	A
	Pulsed drain current @ $T_C=150^\circ\text{C}$ (pulse width: 10us)		58	A
$V_{DSS}$	Drain to source voltage ( $T_J = -55^\circ\text{C}$ to $150^\circ\text{C}$ )		900	V
$V_{TDSS}$	Transient drain to source voltage <sup>a</sup>		1000	V
$V_{GSS}$	Gate to source voltage		$\pm 20$	V
$P_D$	Maximum power dissipation @ $T_C=25^\circ\text{C}$		100	W
$T_C$	Operating temperature	Case	-55 to 150	$^\circ\text{C}$
$T_J$		Junction	-55 to 150	$^\circ\text{C}$
$T_S$	Storage temperature		-55 to 150	$^\circ\text{C}$
$T_{CSOLD}$	Soldering peak temperature		260	$^\circ\text{C}$

### Thermal Resistance

Symbol	Parameter	Typical	Unit
$R_{\theta JC}$	Junction-to-case	1.25	$^\circ\text{C/W}$
$R_{\theta JA}$	Junction-to-ambient	50	$^\circ\text{C/W}$

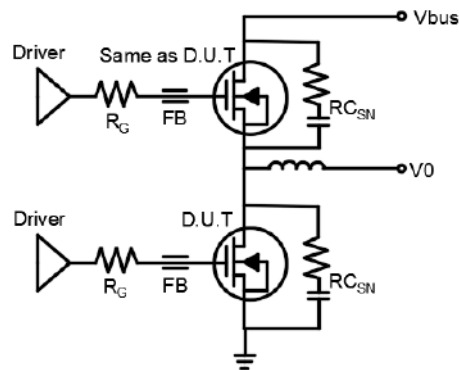
### Electrical Parameters, at $T_J=25^\circ\text{C}$ , unless otherwise specified

Symbol	Min	Typ	Max	Unit	Test Conditions
Forward Device Characteristics					
V <sub>DSS-MAX</sub>	900	-	-	V	V <sub>GS</sub> =0V
BV <sub>DSS</sub>	-	1700	-	V	V <sub>GS</sub> =0V, I <sub>DSS</sub> =250μA
V <sub>GS(th)</sub>	3.5	4	4.5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =500μA
R <sub>DS(on)</sub> <sup>b</sup>	-	-	175	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =25°C
	-	300	-		V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =150°C
I <sub>DSS</sub>	-	5	20	μA	V <sub>DS</sub> =900V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C
	-	50	-	μA	V <sub>DS</sub> =900V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C
I <sub>GSS</sub>	-	-	150	nA	V <sub>GS</sub> =20V
	-	-	-150	nA	V <sub>GS</sub> =-20V
C <sub>ISS</sub>	-	606	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =900V, f=1MHz
C <sub>OSS</sub>	-	40	-	pF	
C <sub>RSS</sub>	-	3	-	pF	
C <sub>O(er)</sub>	-	25	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 to 900V
C <sub>O(tr)</sub>	-	45	-	pF	
Q <sub>G</sub>	-	38	-	nC	V <sub>DS</sub> =600V, V <sub>GS</sub> =0 to 12V, I <sub>D</sub> =10A
Q <sub>GS</sub>	-	8.4	-		
Q <sub>GD</sub>	-	4.7	-		
t <sub>D(on)</sub>	-	44	-	ns	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V to 12V, I <sub>D</sub> =10A, R <sub>G</sub> =40Ω
t <sub>R</sub>	-	16	-		
t <sub>D(off)</sub>	-	40	-		
t <sub>F</sub>	-	12	-		
Reverse Device Characteristics					
V <sub>SD</sub>	-	1.3	-	V	V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =25°C
	-	1.9	-		V <sub>GS</sub> =0V, I <sub>S</sub> =10A, T <sub>J</sub> =25°C
	-	3	-		V <sub>GS</sub> =0V, I <sub>S</sub> =10A, T <sub>J</sub> =150°C
t <sub>RR</sub>	-	16	-	ns	I <sub>S</sub> =10A, V <sub>GS</sub> =0V, d <sub>i</sub> /d <sub>t</sub> =1000A/us, V <sub>DD</sub> =600V
Q <sub>RR</sub>	-	26	-	nC	

#### Notes:

- Off-state spike duty cycle  $< 0.01$ , spike duration  $< 2\mu s$
- Dynamic on-resistance; see Fig. 18 and 19 for test circuit and conditions

### Circuit Implementation



Recommended Drive Circuit

Recommended gate drive: (0 V, 12 V) with  $R_{G(tot)} = 41 \Omega$ , where  $R_{G(tot)} = R_G + R_{Driver}$

Gate Ferrite Bead (FB)	Gate Resistance1 ( $R_G$ )	RC Snubber ( $RC_{SN}$ )
MPZ1608S471ATA00	40 $\Omega$	69 pF + 15 $\Omega$

Notes:

- c.  $RC_{sn}$  should be placed as close as possible to the drain pin
- d. The layout and wiring of the drive circuit should be as short as possible

Typical Characteristics, at  $T_c=25^\circ\text{C}$ , unless otherwise specified

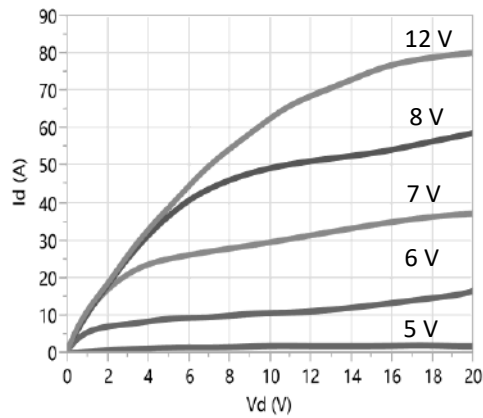


Figure 1. Typical Output Characteristics  $T_j=25^\circ\text{C}$

Parameter:  $V_{GS}$

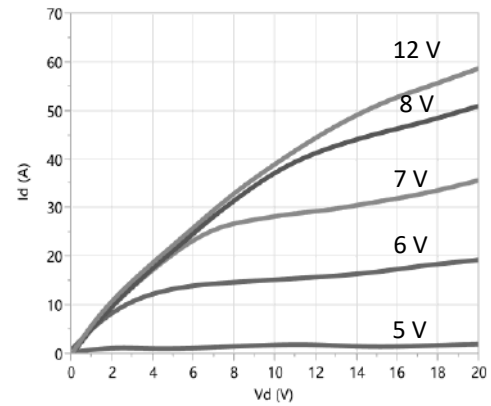


Figure 2. Typical Output Characteristics  $T_j=150^\circ\text{C}$

Parameter:  $V_{GS}$

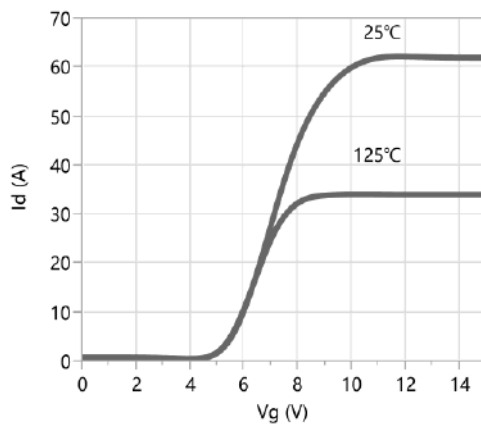


Figure 3. Typical Transfer Characteristics

$V_{DS}=10\text{V}$ , Parameter:  $T_j$

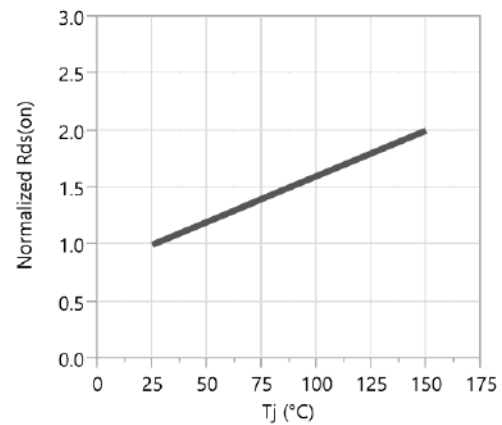


Figure 4. Normalized On-resistance

$I_D=4\text{A}$ ,  $V_{GS}=8\text{V}$

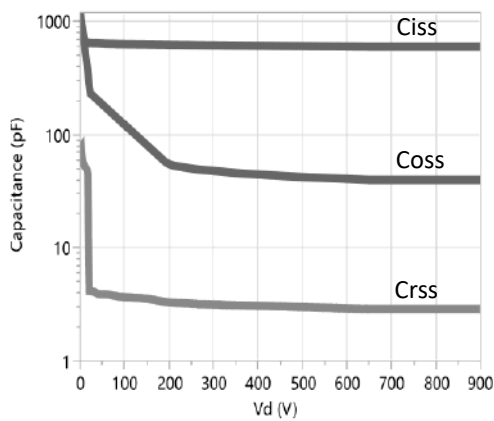


Figure 5. Typical Capacitance

$V_{GS}=0\text{V}$ ,  $f=1\text{MHz}$

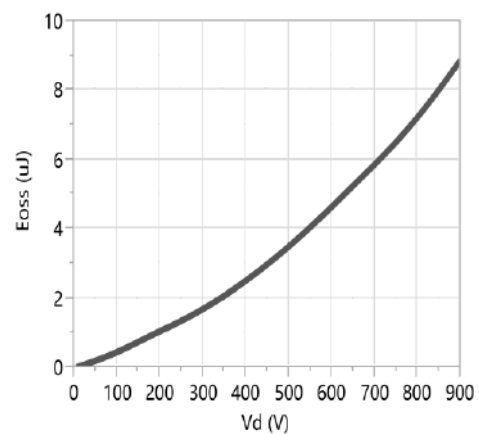


Figure 6. Typical  $C_{oss}$  Stored Energy

Typical Characteristics, at  $T_C=25^\circ\text{C}$ , unless otherwise specified

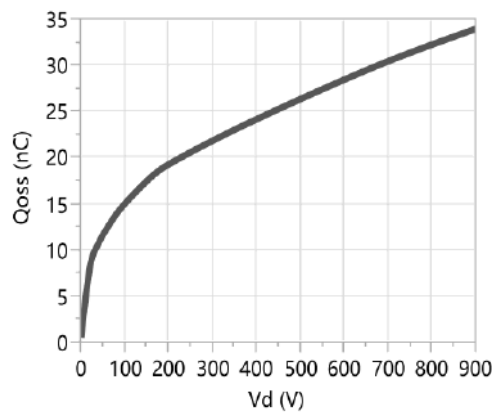


Figure 7. Typical Qoss

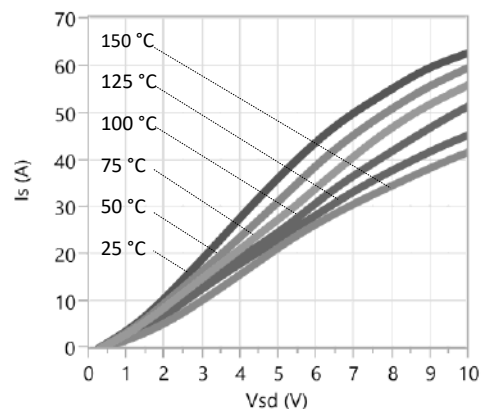


Figure 8. Forward Characteristic of Rev. Diode

$I_s=f(V_{sd})$ , Parameter  $T_j$

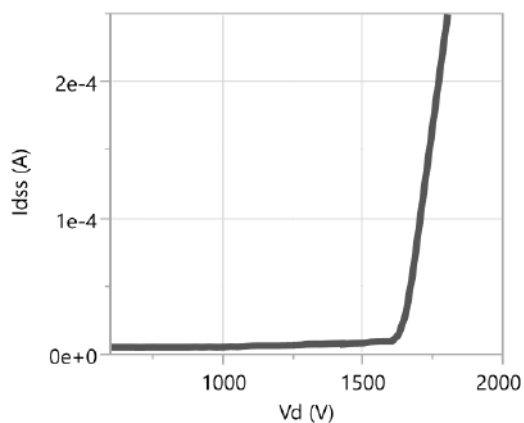


Figure 9. Drain-Source Breakdown Voltage

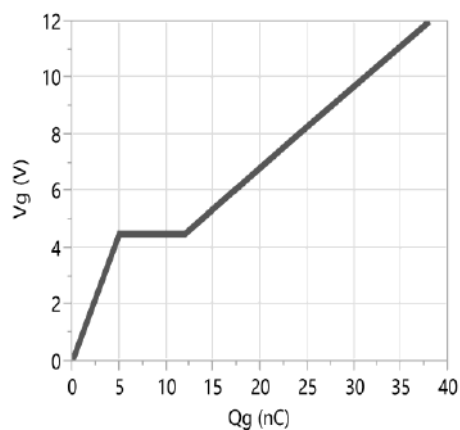


Figure 10. Typical Gate Charge

$I_{DS}=10\text{A}$ ,  $V_{DS}=600\text{V}$

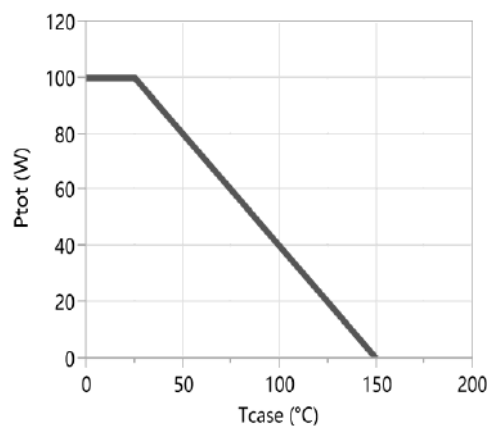


Figure 11. Power Dissipation

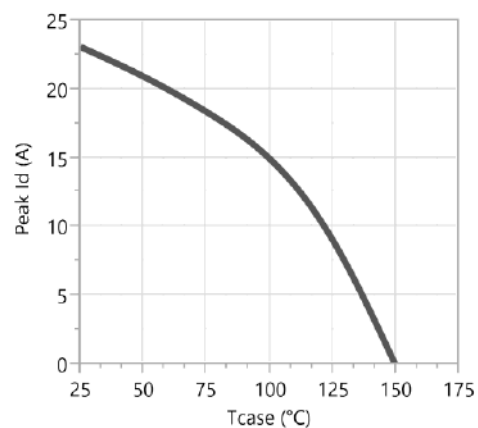
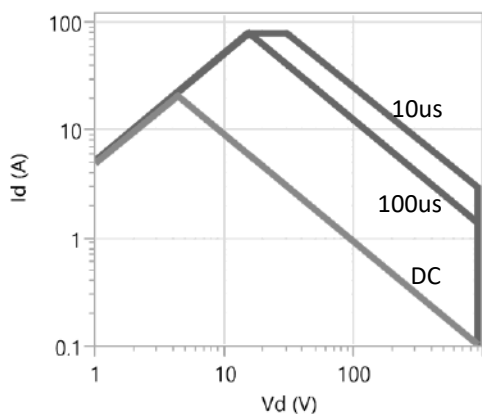
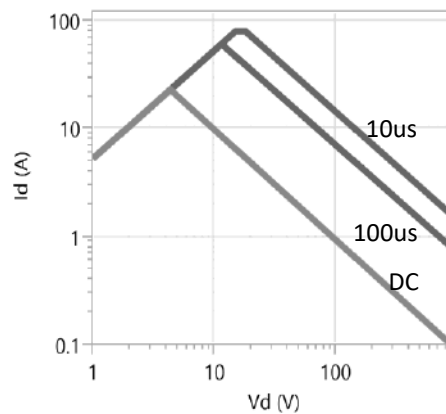


Figure 12. Current Derating

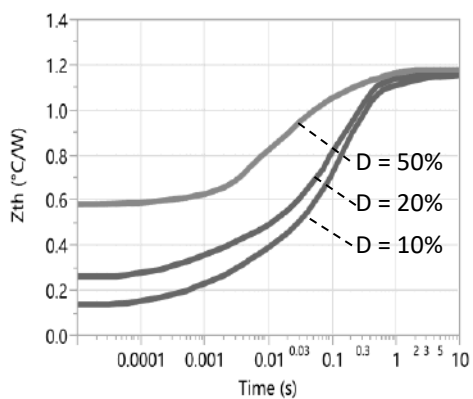
Typical Characteristics, at  $T_c=25^\circ\text{C}$ , unless otherwise specified



**Figure 13. Safe operating Area  $T_c=25^\circ\text{C}$**   
(calculated based on thermal limit)



**Figure 14. Safe operating Area  $T_c=80^\circ\text{C}$**   
(calculated based on thermal limit)



**Figure 15. Transient Thermal Resistance**

### Test Circuits and Waveforms

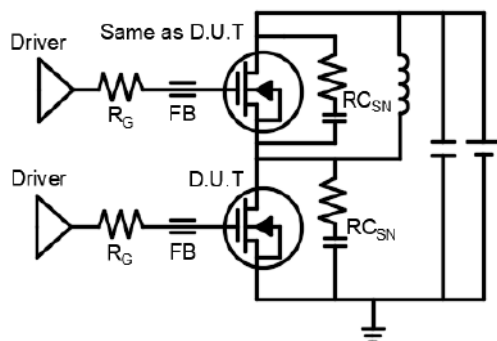


Figure 16. Switching Time Test Circuit

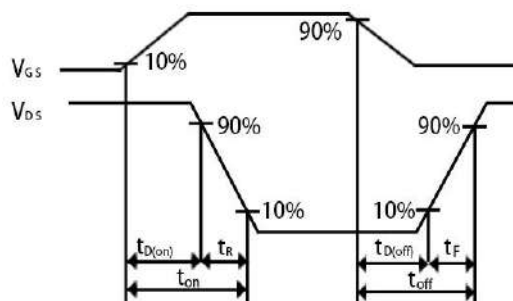


Figure 17. Switching Time Waveform

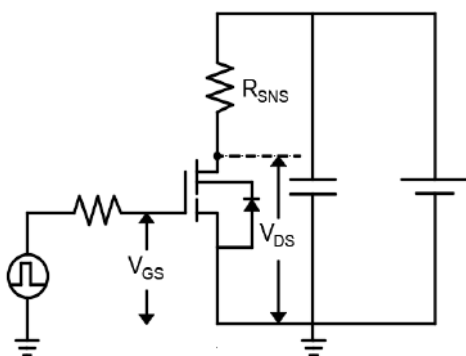


Figure 18. Dynamic  $R_{DS(on)}$  Test Circuit

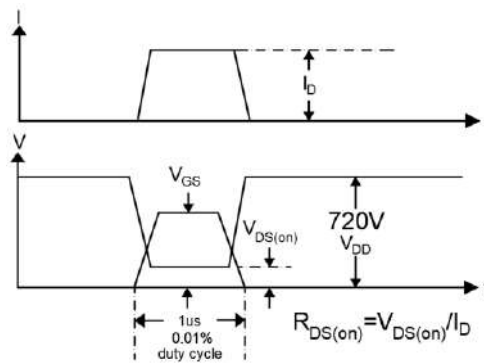


Figure 19. Dynamic  $R_{DS(on)}$  Waveform

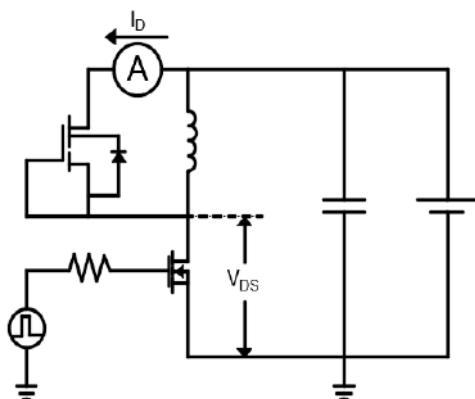


Figure 20. Diode Characteristic Test Circuit

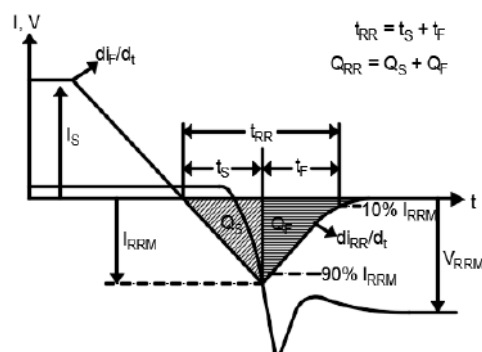


Figure 21. Diode Recovery Waveform

### Design Considerations

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

Before evaluating Ascend's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

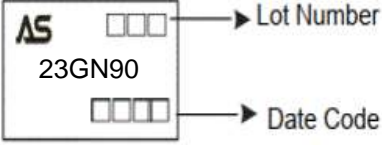
**When Evaluating Ascend's GaN Devices:**

DO	DO NOT
Make sure the traces are as short as possible for both drive and power loops to minimize parasitic inductance	Using Ascend's devices in GDS board layouts
Use the test tool with the shortest inductive loop, and make sure test points should be placed close enough	Use differential mode probe or probe ground clip with long wires
Minimize the lead length of TO packages when installing them to PCB	Use long traces in drive circuit, or long lead length of the devices



### Ordering and Marking Information

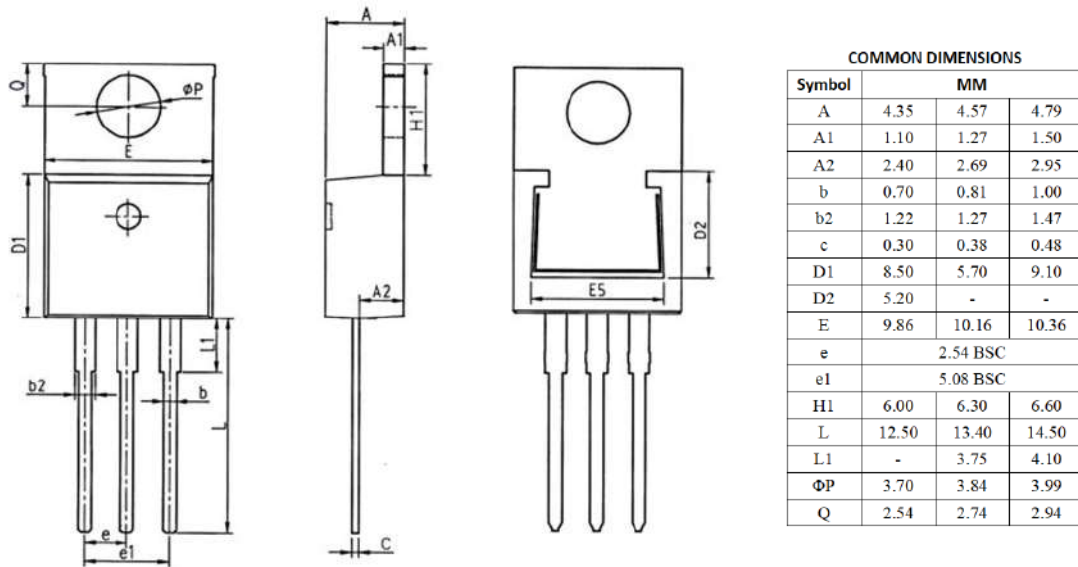
Ordering Device No.	Marking	Package	Packing	Quantity
ASDM23GN90P-T	23GN90	TO-220	Tube	50/Tube

PACKAGE	MARKING
TO-220	 <p>AS    23GN90</p> <p>Lot Number (3 digits)</p> <p>Date Code (4 digits)</p>

### Package Outlines

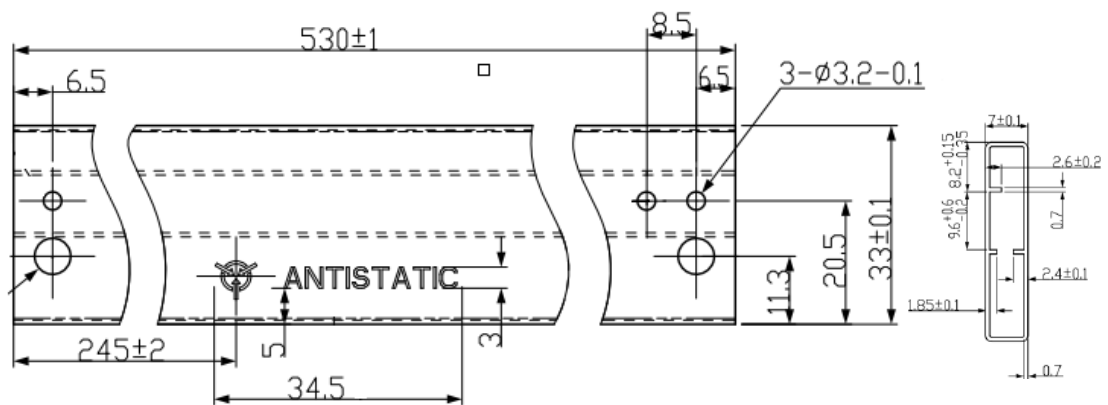
### 3 Lead TO-220 Package

Pin 1: Gate; Pin 2: Source; Pin 3: Drain; Tab: Source



### Tube Information

Dimensions are shown in millimeters



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